



*Industrial Computing Platform Partner*

# **AEC-6911**

**With 2.5" HDD**

## **Environment Test Report**

**Report NO: 09P020017**

Issued by: **Rex-Chang** / **02/20/2009**  
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**Test Engineer** **Date**

Reviewed by: **Wenyuan Yang** / **02/20/2009**  
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**Manager** **Date**

# Test item list

1. <i>Test item list</i> -----	2
2. <i>Temperature rise test</i> -----	3
3. <i>Temperature cycle operation test</i> -----	7
4. <i>High temperature storage test</i> -----	8
5. <i>Low temperature storage test</i> -----	9
6. <i>Humidity test</i> -----	10
7. <i>Cold start and hot start test</i> -----	11

## Test Configuration:

Num	Item	Spec
1.	Control Box:	AEC- 6911
	1. Main Board	AAEON COM-945GSE Rev. A1.0 (BIOS: AEC-6911 BIOS V0.4)
	2. CPU	Intel N270 / 1.6GHz
	3. Industrial Memory	INNODisk 1GB * 1 / DDR2 667 / V59C1512804QCF3I
	5. Industrial HDD	Fujitsu MHV2040AC / 40GB
	6. I/O Board	T073 A1.2
	7. Adapter	FSP FSP120-AAB 19V/6.32A 120W

# Temperature rise test

**Test Date:** 02-19-2009

**Test Product:** AEC-6911

**Test Site:** AAEON QA Internal Lab.

**Test Standard:** Reference EN 61131-2(94), UL508 (94)

**Temperature Measurement:**

40 Channel Thermal Recorder:  
YOKOGAWA Inc,  
Model: DA100-13-1D  
Date of Calibration: 12/07/08  
Serial Number: 12A323190

**Test Condition:**

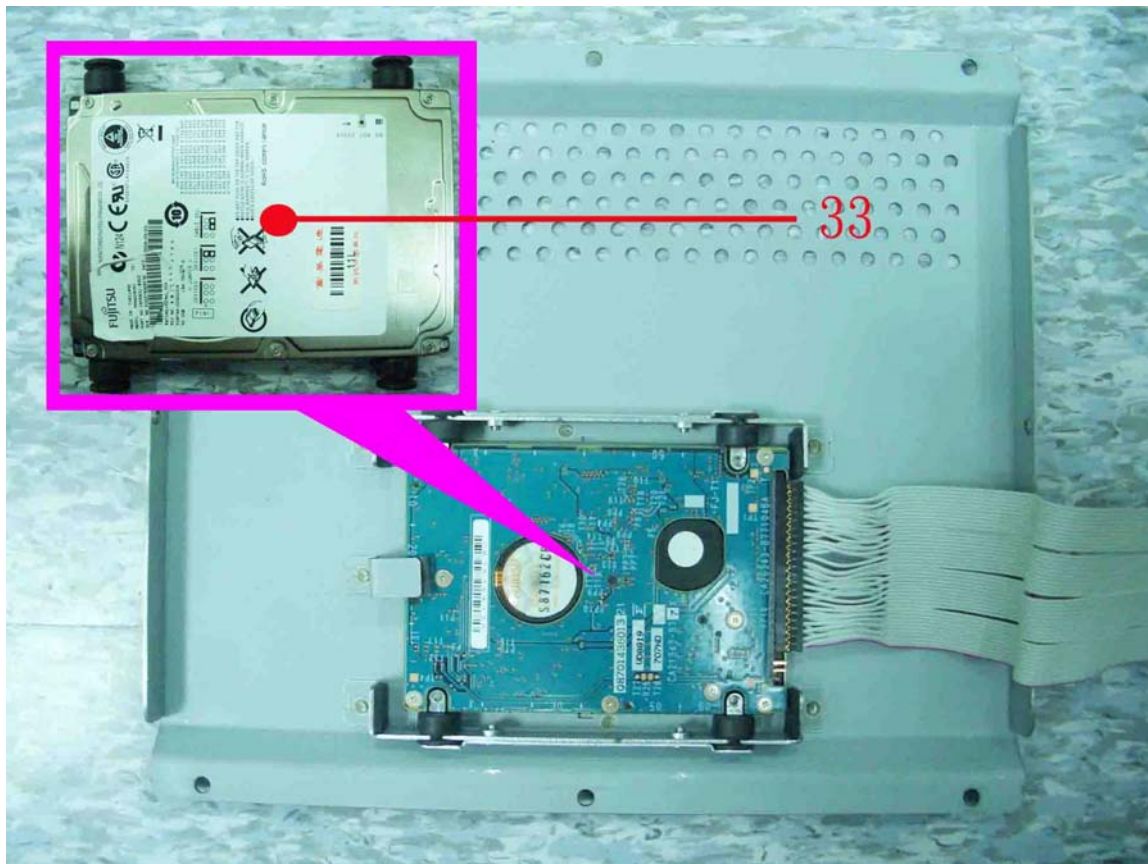
Ambient temperature: 50dC  
Continuous running till thermal stability (within less than 1°C)

**Test Software:**

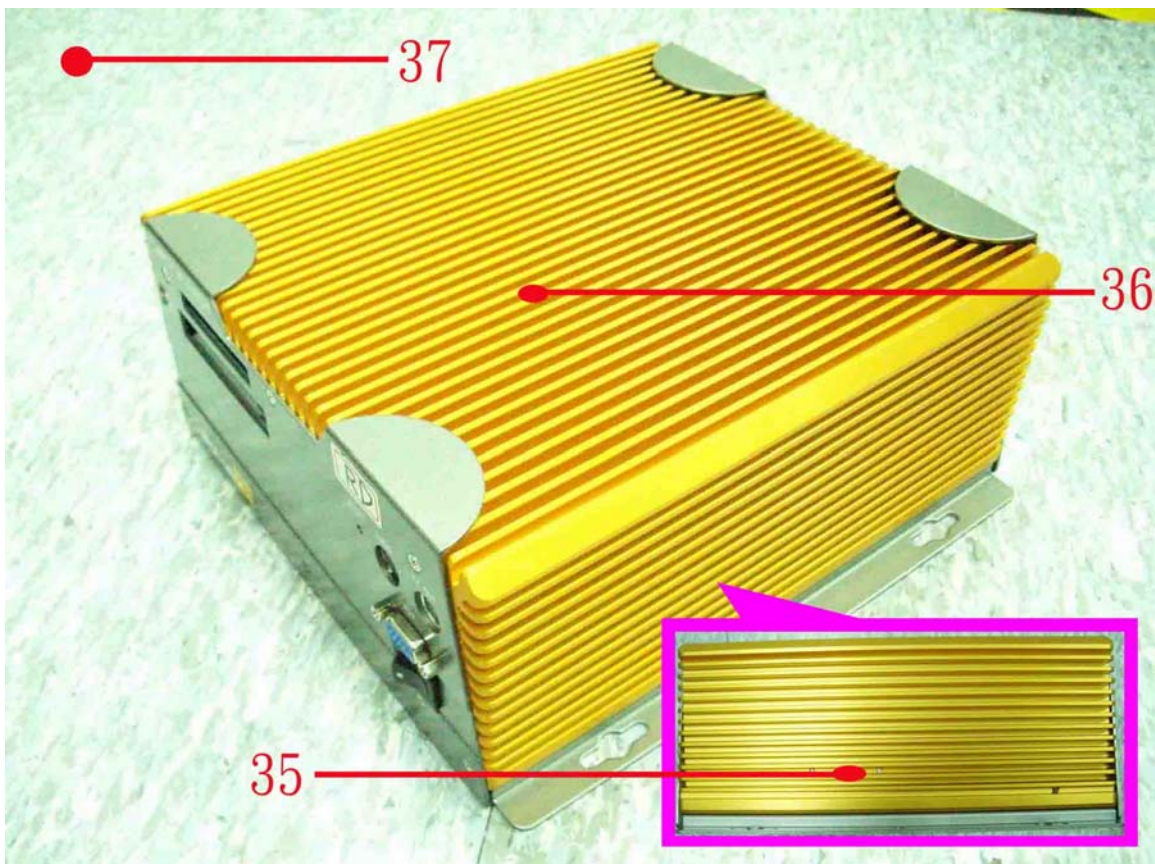
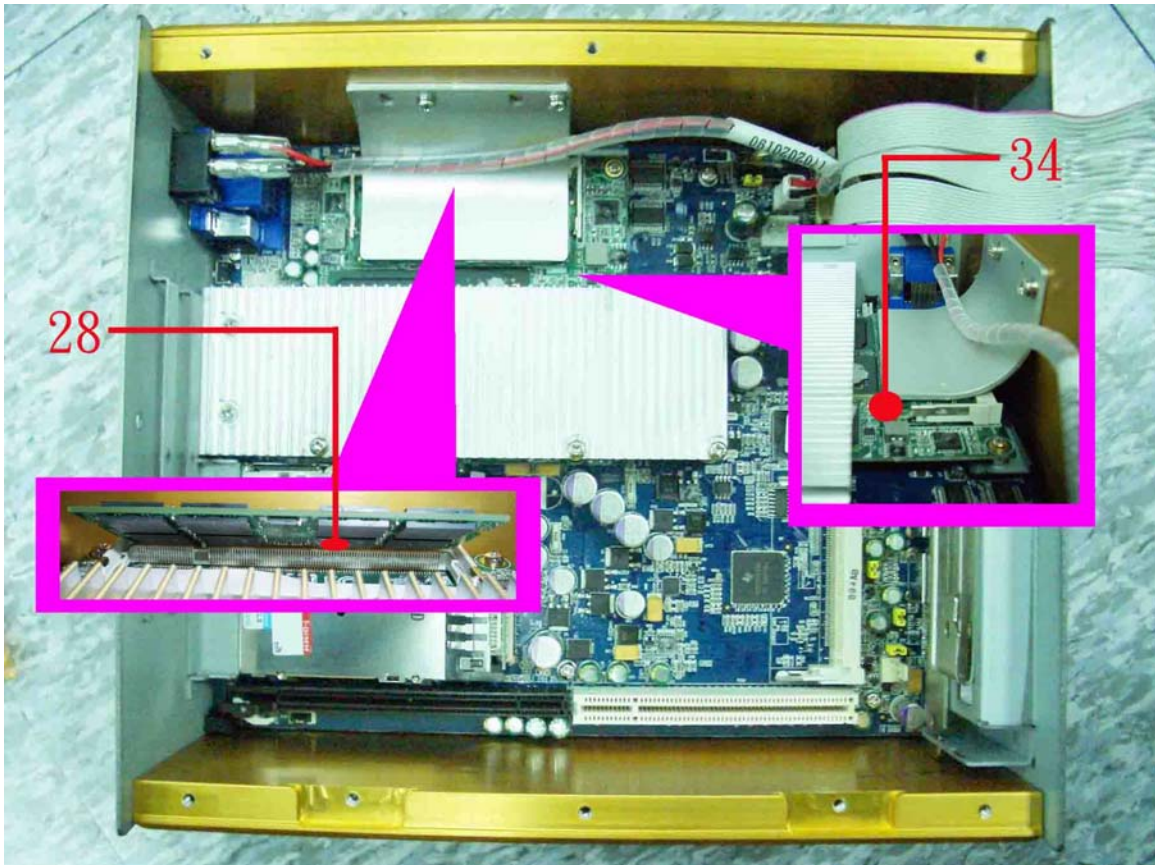
Windows XP / Run PassMark Burn In Test 5.1

**Terminal Recorder:**

Measuring Thermal Couple Position :



# Temperature rise test



# Temperature rise test

## Thermal profile data:

### AEC-6911

Point	Temp. Stage(°C)	Spec	50	25
<b>I/O Board T073</b>				
1. L6 - COIL.3.3uH.SMD.GOTREND.GSTC135P-3R3MF		125	63.2	38.2
2. L7 - COIL.2.2uH.SMD.GOTREND.GSTC135P-2R2MF		125	65.8	35.8
3. L8 - COIL.2.2uH.SMD.GOTREND.GSTC135P-2R2MF		125	68.5	38.5
4. L9 - COIL.3.3uH.SMD.GOTREND.GSTC135P-3R3MF		125	65.4	35.4
5. U17 - Regulator.LINEAR.LTC3780EUH#PBF		85	76.6	46.6
6. U15 - SSOP 28P.Clock Buffer.ICS.ICS9DB104FLFT		115	79.2	49.2
7. U34 - GigaBit Ethernet Chipset.Intel.PC82573L		95	70.1	40.1
8. U2 - SSOP16 MOSFET.LINEAR-TECHNOLOGY.LTC1778EGN		85	70.7	40.7
9. U11 - SOP 8P.Clock Output Buffer.ICS.ICS9112M-16LF-T		95	73.5	43.5
10. Q11 - TO-252AA.N-Channel MOSFET.FAIRCHILD.FDD5670		125	70.1	40.1
11. U19 - (TF) LPC to 4 UART.FINTEK.F81216DG		95	73.8	43.8
12. U27 - (TF) RS-485 Transceivers.SIPEX.SP485ECN-L		95	70.8	40.8
<b>COM-945GSE</b>				
13. Intel CPU.Diamondville.N270.1.6GHz/FSB 533MHz		90	81.5	51.5
14. U3 - (TF) Intel 945GSE Express Chipset.Intel.QG82945GSE SLB2R		105	76.5	46.5
15. U4 - (TF) ICH7M.Intel.NH82801GBM SL8YB		100	89.3	59.3
16. U15 - (TF) WatchDog.Fintek.F75111RG		115	76.5	46.5
17. U24 - (TF) Power Controller.for Dual Channel DDR.Intersil.ISL6537CRZ		100	95.1	65.1
18. U6 - (TF) PCI-E GigaBit Ethernet Chipset.Intel.WG82574L SLBA8		109	79.3	49.3
19. U22 - (TF) PHILIPS.74LVC07AD-T		125	78.1	48.1
20. U10 - (TF) CLOCK GENERATOR.IDT.9LPRS501PGLF		100	91.9	61.9
21. L10 - (TF) COIL. GOTREND.GSTC063P-1R5MN		125	105.8	75.8
22. U7 - (TF) SPI Bus Serial EEPROM.ATMEL.AT25080AN-10SU-2.7		125	73.9	43.9
23. Q9 - (TF) PWR. P-Channel MOSFET.ANPEC.APM4463KC-TRL		125	81.4	51.4
24. Q39 - (TF) PWR.Dual N MOSFET.30V.9.1A/6.8A.CET.CEM3138		125	87.7	57.7
25. U25 - (TF) IMVP6 Two Phase PWM.Intersil.ISL6262ACRZ-T		130	80.7	50.7
26. U19 - (TF) Voltage Detecting.System Resetting		110	77.8	47.8
27. Q25 - (TF) PWR. N-Channel.30V.12A.ANPEC.APM4410KC-TRL		125	105.2	75.2
28.Memory		85	75.2	45.2
29. Q37 - (TF) PWR.Dual N MOSFET.30V.9.1A/6.8A.CET.CEM3138		125	101.6	71.6
30. Q15 - (TF) REG.Linear Regulator.ATC.AP1084DL-ADJ		125	86.7	56.7
<b>Any Tm value showed in red words which meaning the value over the Tc degree C of this device specification.</b>				

# Temperature rise test

Point	Temp. Stage(°C)	Spec	50	25
COM-945GSE				
31. U9 - (TF) Switching Bulk.Regulator.withbuilt in Mosfet.FEELING.FP6102DR-LF		115	97.8	67.8
32. Q7 - (TF) PNP.Amp.ON.BCP69T1G		125	85.3	55.3
33.HDD		85	63.8	33.8
34.Control Box Inside Air Temperature		N/A	69.3	39.3
35.Control Box External Surface - 1		N/A	61.7	31.7
36.Control Box External Surface - 2		N/A	62.0	32.0
37.Chamber Air Temperature		N/A	50.1	20.1
<b>Any Tm value showed in red words which meaning the value over the Tc degree C of this device specification.</b>				

## Sample Configuration & Quantity Under Test:

Quantity: 1 (AEC-6911)

## Test Result:

No problem was found during the temperature rise operation test.

# Temperature cycle test

**Test Date:** 01-20~22-2009

**Test Product:** AEC-6911

**Test Site:** AAEON QA Internal Lab.

**Test Standard:** Reference IEC68-2-14 Testing procedures  
Test N: Change of temperature Test

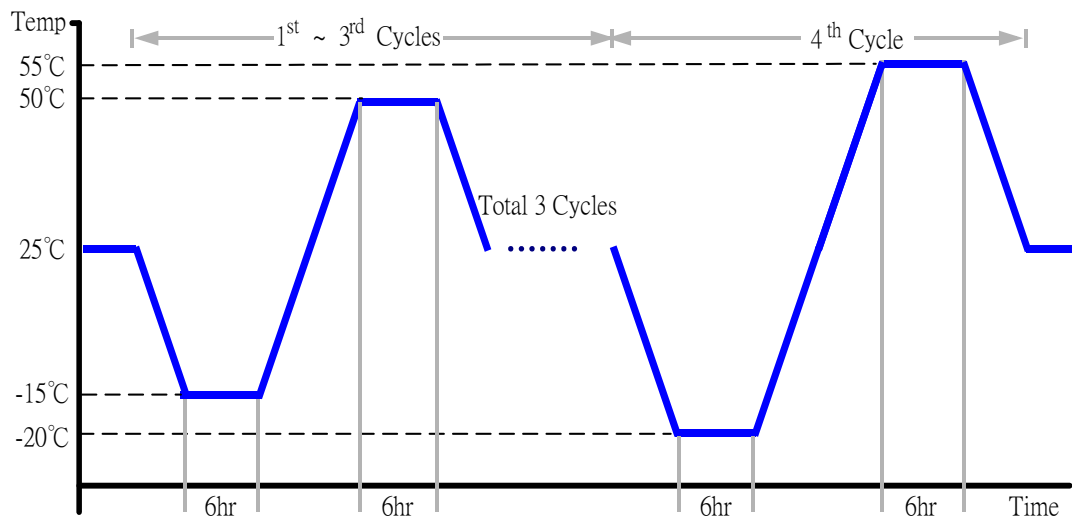
**Test Equipment:**

Programmable Temperature & Humidity Chamber  
K.SON. INS. TECH. CORP.

Model: THS-B6T-150+LN2  
Date of Calibration: 04/17/08  
Serial Number: 6488KT

**Test Condition:**

1. Test Low Temperature: -15°C (1~3 cycles)  
-20°C (4<sup>th</sup> cycle)
2. Test High Temperature: 50°C (1~3 cycles)  
55°C (4<sup>th</sup> cycle)
3. Test dwell time: 6Hrs
4. Temperature slope: 2°C/min
5. Test cycle: 4 cycles
6. Test Environment Curve:



**Sample Configuration & Quantity Under Test:**

Quantity: 1 (AEC-6911)

**Test Result:**

No problem was found during the temperature operation cycle test.

**Test Date:** 02-15~17-2009

**Test Product:** AEC-6911

**Test Site:** AAEON QA Internal Lab.

**Test Standard:** Reference IEC 68-2-2 Testing procedures  
Test Bb: Dry Heat Test (Non-operation)

**Test Equipment:**

Programmable Temperature & Humidity Chamber  
K.SON. INS. TECH. CORP.  
Model: THS-D7S-100+1 N2  
Date of Calibration: 12/13/08  
Serial Number: 3898

**Testing Item:**

1. Test Temperature: 70°C
2. Test Times: 48Hrs
3. Test Software: Windows XP / Run PassMark Burn In Test 5.1 Pro
4. Test Environment Curve:



**Sample Configuration & Quantity Under Test:**

Quantity: 1 (AEC-6911)

**Test Result:**

No problem was found after the high temperature storage test.



**Test Date:** 02-10~12-2009

**Test Product:** AEC-6911

**Test Site:** AAEON QA Internal Lab.

**Test Standard:** Reference IEC 68-2-1 Testing procedures  
Test Ab: Cold Test (Non-operation)

**Test Equipment:**

Programmable Temperature & Humidity Chamber  
K.SON. INS. TECH. CORP.  
Model: THS-D7S-100+1 N2  
Date of Calibration: 12/13/08  
Serial Number: 3898

**Testing Item:**

1. Test Temperature: -20°C
2. Test Times: 48Hrs
3. Test Software: Windows XP / Run PassMark Burn In Test 5.1 Pro
4. Test Environment Curve:



**Sample Configuration & Quantity Under Test:**  
Quantity: 1 (AEC-6911)

**Test Result:**

No problem was found after the low temperature storage test.

**Test Date:** 02-17~19-2009

**Test Product:** AEC-6911

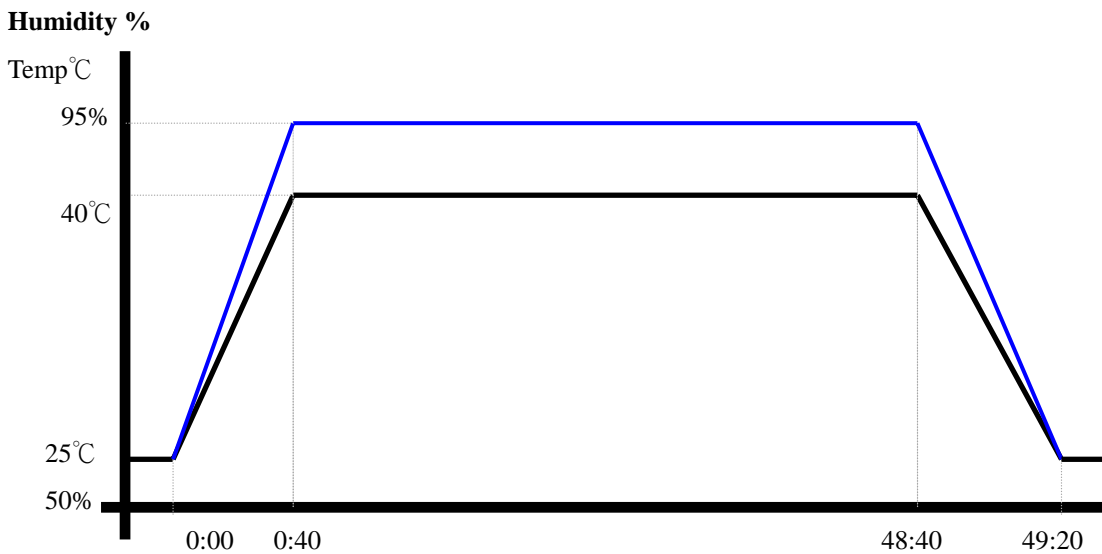
**Test Site:** AAEON QA Internal Lab.

**Test Standard:** Reference IEC 68-2-3 Testing procedures  
Test Ca: Damp heat, steady state (Non-operation)

**Test Equipment:**  
Programmable Temperature & Humidity Chamber  
K.SON. INS. TECH. CORP.  
Model: THS-D7S-100+1 N2  
Date of Calibration: 12/13/08  
Serial Number: 3898

**Testing Item:**

1. Test Temperature: 40°C
2. Test Humidity: 95%RH
3. Test Times: 48Hrs
4. Test Software: Windows XP / Run PassMark Burn In Test 5.1 Pro
5. Test Environment Curve:



**Sample Configuration & Quantity Under Test:**  
Quantity: 1 (AEC-6911)

**Test Result:**  
No problem was found after the humidity storage test.

# Cold start and hot start test

**Test Date:** 01-22~23-2009

**Test Product:** AEC-6911

**Test Site:** AAEON QA Internal Lab.

**Test Standard:** Reference IEC 68-2-14 Testing procedures  
Test N: Change of temperature Test

**Test Equipment:**  
Programmable Temperature & Humidity Chamber  
K.SON. INS. TECH. CORP.  
Model: THS-B6T-150+LN2  
Date of Calibration: 04/17/08  
Serial Number: 6488KT

**Test Condition:**

Parameters	Description
T1	-20°C
T2	55°C
t1	4 hrs
t2, t6	2 hrs
t4, t5	1hrs
t, t3	2°C/min
n (Cycle)	1

t = temprature slope  
t , t1, t6: Power Off  
t2: Power on/off test 10 times (on 2 min / off 5min)  
t3, t4: Run PassMark Burn In Test  
t5: Win XP Software restart test 3 times  
Test Software:Windows XP

**Test Result:**

- a. No problem was found during the cold start test.
- b. No problem was found during the hot start test.